

# NIST - ASM International Virtual Additive Manufacturing Data Management Workshop

27-28 October 2020

NIST in partnership with ASM International will hold a virtual additive manufacturing (AM) data management workshop.

## Workshop Purpose

Establish a strategic path forward regarding needed AM data management. Build consensus between industry, government, and academia as to the specific objectives, challenges, & approaches to be pursued in order to accelerate AM part deployment and reduce the time and cost associated with **AM process qualification**. Inform NIST programmatic strategy in AM data science. The launch pad for this event is based on fundamental tenets established in prior government, industry and academia workshops.

## Workshop Structure

The workshop will be executed over a two-day period. The workshop will kick off with a plenary session consisting of SME addressing the **Findability**, **Accessibility**, **Interoperability**, and **Reusability (FAIR)** of AM data. Participants will be divided into working group(s) and spend approximately 4 hours addressing the What, Why, Where, and How questions associated with implementing FAIR from an end user perspective.

<b>Fair -</b>	Metadata and data should be easy to find for both humans and computers.
<b>Accessible -</b>	Once the user finds the required data, she/he needs to know how can they be accessed, possibly including authentication and authorization.
<b>Interoperable -</b>	The data usually need to be integrated with other data. In addition, the data need to interoperate with applications or workflows for analysis, storage, and processing.

<b>Reusable -</b>	The ultimate goal of FAIR is to optimize the reuse of data. To achieve this, metadata and data should be well-described so that they can be replicated and/or combined in different settings.
-------------------	---

**NIST**  
**ASM International**

**Event Point of Contacts**

**Technical**

William E. Frazier, PhD,  
FASM

Pilgrim Consulting LLC

[frazierwe@gmail.com](mailto:frazierwe@gmail.com)

**Technical**

Yan Lu, PhD

NIST

[Yan.lu@nist.gov](mailto:Yan.lu@nist.gov)

**Administrative**

Ray Fryan

ASM International

[Ray.Fryan@asminternational.org](mailto:Ray.Fryan@asminternational.org)